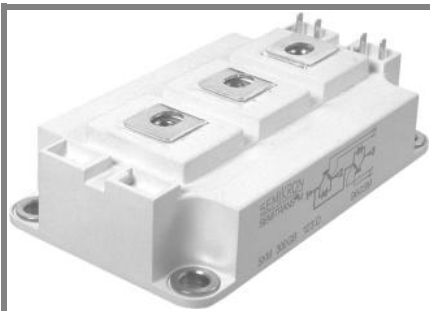


SKM 200GB125D



SEMITRANS® 3

Ultra Fast IGBT Modules

SKM 200GB125D

SKM 200GAL125D

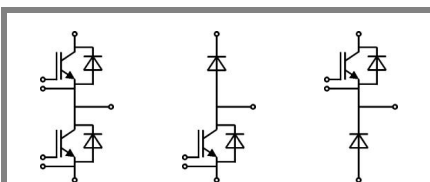
SKM 200GAR125D

Features

- N channel , homogeneous Si
- Low inductance case
- Short tail current with low temperature dependence
- High short circuit capability, self limiting to $6 \times I_{Cnom}$
- Fast & soft inverse CAL diodes
- Isolated copper baseplate using DCB Direct Copper Bonding Technology
- Large clearance (13 mm) and creepage distance (20 mm)

Typical Applications

- Switched mode power supplies at $f_{sw} > 20$ kHz
- Resonant inverters up to 100 kHz
- Inductive heating
- Electronic welders at $f_{sw} > 20$ kHz



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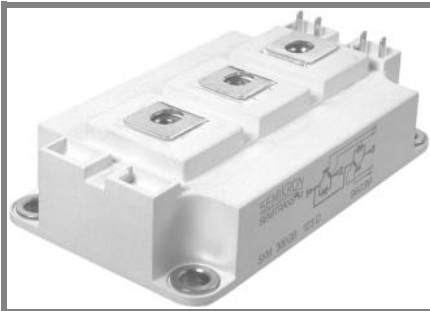
GAL

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Absolute Maximum Ratings		$T_c = 25^\circ\text{C}$, unless otherwise specified			
Symbol	Conditions	Values		Units	
IGBT					
V_{CES}	$T_j = 25^\circ\text{C}$	1200		V	
I_C	$T_j = 150^\circ\text{C}$	$T_{case} = 25^\circ\text{C}$	200	A	
		$T_{case} = 80^\circ\text{C}$	160	A	
I_{CRM}	$I_{CRM} = 2 \times I_{Cnom}$	300		A	
V_{GES}		± 20		V	
t_{psc}	$V_{CC} = 600\text{ V}; V_{GE} \leq 20\text{ V}; T_j = 125^\circ\text{C}$ $V_{CES} < 1200\text{ V}$	10		μs	
Inverse Diode					
I_F	$T_j = 150^\circ\text{C}$	$T_{case} = 25^\circ\text{C}$	200	A	
		$T_{case} = 80^\circ\text{C}$	130	A	
I_{FRM}	$I_{FRM} = 2 \times I_{Fnom}$	300		A	
I_{FSM}	$t_p = 10\text{ ms}; \sin.$	$T_j = 150^\circ\text{C}$	1440		A
Freewheeling Diode					
I_F	$T_j = ^\circ\text{C}$	$T_c = 25^\circ\text{C}$	200	A	
		$T_c = 80^\circ\text{C}$	130	A	
I_{FRM}	$I_{FRM} = 2 \times I_{Fnom}$	300		A	
I_{FSM}	$t_p = 10\text{ ms};$	$T_j = 150^\circ\text{C}$	1440		A
Module					
$I_{t(RMS)}$		500		A	
T_{vj}		- 40...+ 150		$^\circ\text{C}$	
T_{stg}		- 40...+ 125		$^\circ\text{C}$	
V_{isol}	AC, 1 min.	4000		V	

Characteristics		$T_c = 25^\circ\text{C}$, unless otherwise specified			
Symbol	Conditions	min.	typ.	max.	Units
IGBT					
$V_{GE(th)}$	$V_{GE} = V_{CE}, I_C = 6\text{ mA}$	4,5	5,5	6,5	V
I_{CES}	$V_{GE} = 0\text{ V}, V_{CE} = V_{CES}$		0,15	0,45	mA
V_{CE0}		$T_j = 25^\circ\text{C}$	1,5	1,75	V
		$T_j = 125^\circ\text{C}$			V
r_{CE}	$V_{GE} = 15\text{ V}$	$T_j = 25^\circ\text{C}$	12	14	$\text{m}\Omega$
		$T_j = 125^\circ\text{C}$			$\text{m}\Omega$
$V_{CE(sat)}$	$I_{Cnom} = 150\text{ A}, V_{GE} = 15\text{ V}$		3,3	3,85	V
C_{ies}			10	13	nF
C_{oes}	$V_{CE} = 25, V_{GE} = 0\text{ V}$		1,5	2	nF
C_{res}	$f = 1\text{ MHz}$		0,8	1,2	nF
Q_G	$V_{GE} = 0\text{ V} - +20\text{ V}$		1300		nC
R_{Gint}	$T_j = ^\circ\text{C}$		2,5		Ω
$t_{d(on)}$	$R_{Gon} = 4\ \Omega$	$V_{CC} = 600\text{ V}$ $I_{Cnom} = 150\text{ A}$	75		ns
t_r			36		ns
E_{on}	$R_{Goff} = 4\ \Omega$	$T_j = 125^\circ\text{C}$ $V_{GE} = \pm 15\text{ V}$	14		mJ
$t_{d(off)}$			420		ns
t_f			25		ns
E_{off}					mJ
$R_{th(j-c)}$	per IGBT			0,09	K/W

SKM 200GB125D



SEMITRANS® 3

Ultra Fast IGBT Modules

SKM 200GB125D

SKM 200GAL125D

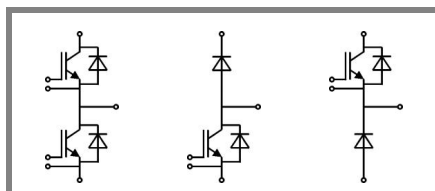
SKM 200GAR125D

Features

- N channel , homogeneous Si
- Low inductance case
- Short tail current with low temperature dependence
- High short circuit capability, self limiting to $6 \times I_{cnom}$
- Fast & soft inverse CAL diodes
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Typical Applications

- Switched mode power supplies at $f_{sw} > 20$ kHz
- Resonant inverters up to 100 kHz
- Inductive heating
- Electronic welders at $f_{sw} > 20$ kHz



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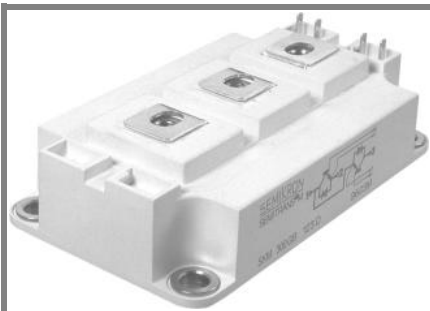
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Characteristics					
Symbol	Conditions	min.	typ.	max.	Units
Inverse Diode					
$V_F = V_{EC}$	$I_{Fnom} = 150$ A; $V_{GE} = 0$ V	$T_j = 25$ °C _{chiplev.}	2	2,5	V
		$T_j = 125$ °C _{chiplev.}	1,8		V
V_{F0}		$T_j = 25$ °C	1,1	1,2	V
		$T_j = 125$ °C			V
r_F		$T_j = 25$ °C	6	8,7	mΩ
		$T_j = 125$ °C			mΩ
I_{RRM}	$I_{Fnom} = 150$ A	$T_j = 125$ °C	230		A
Q_{rr}	$di/dt = 5500$ A/μs		24		μC
E_{rr}	$V_{GE} = 0$ V; $V_{CC} = 600$ V				mJ
$R_{th(j-c)D}$	per diode			0,25	K/W
Freewheeling Diode					
$V_F = V_{EC}$	$I_{Fnom} = 150$ A; $V_{GE} = 0$ V	$T_j = 25$ °C _{chiplev.}	2	2,5	V
		$T_j = 125$ °C _{chiplev.}	1,8		V
V_{F0}		$T_j = 25$ °C	1,1	1,2	V
		$T_j = 125$ °C			V
r_F		$T_j = 25$ °C	6	8,7	V
		$T_j = 125$ °C			V
I_{RRM}	$I_{Fnom} = 150$ A	$T_j = 125$ °C	230		A
Q_{rr}	$di/dt = 5500$ A/μs		24		μC
E_{rr}	$V_{GE} = 0$ V; $V_{CC} = 600$ V				mJ
$R_{th(j-c)FD}$	per diode			0,25	K/W
Module					
L_{CE}			15	20	nH
$R_{CC'+EE'}$	res., terminal-chip	$T_{case} = 25$ °C	0,35		mΩ
		$T_{case} = 125$ °C	0,5		mΩ
$R_{th(c-s)}$	per module			0,038	K/W
M_s	to heat sink M6		3	5	Nm
M_t	to terminals M6		2,5	5	Nm
w				325	g

This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, Chapter IX.

This technical information specifies semiconductor devices but promises no characteristics. No warranty or guarantee expressed or implied is made regarding delivery, performance or suitability.

SKM 200GB125D



SEMITRANS® 3

Ultra Fast IGBT Modules

SKM 200GB125D

SKM 200GAL125D

SKM 200GAR125D

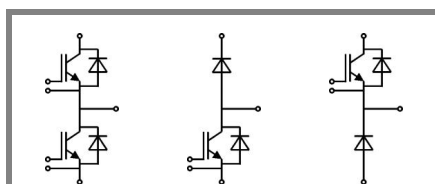
Features

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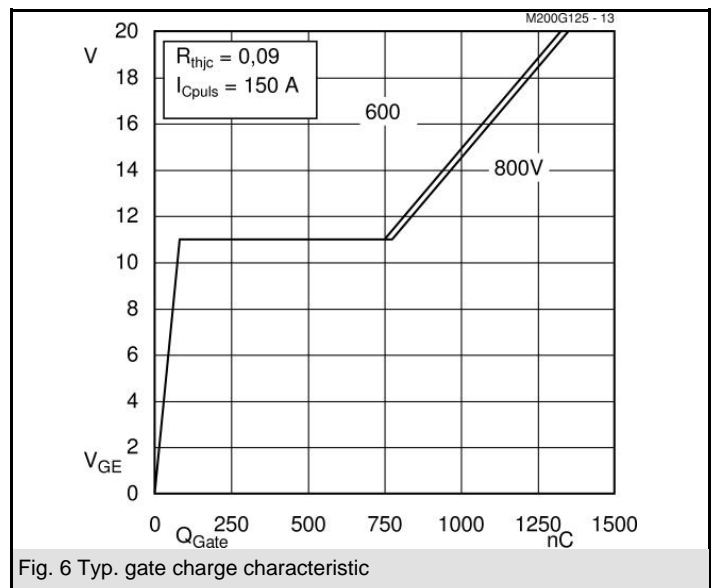
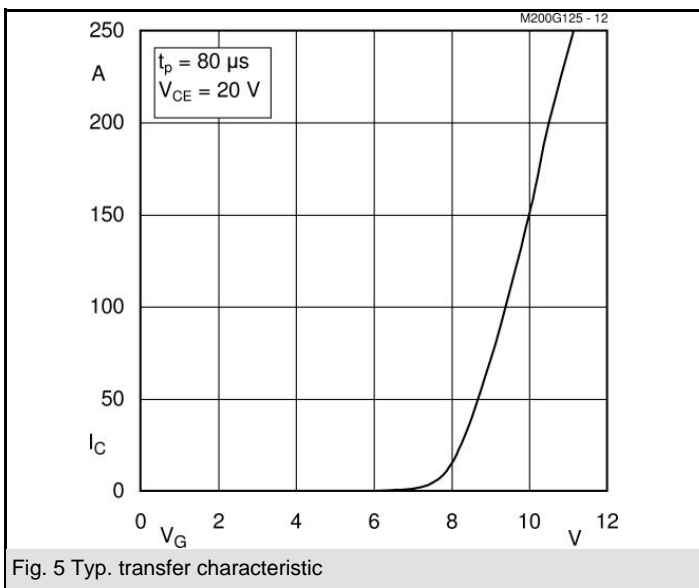
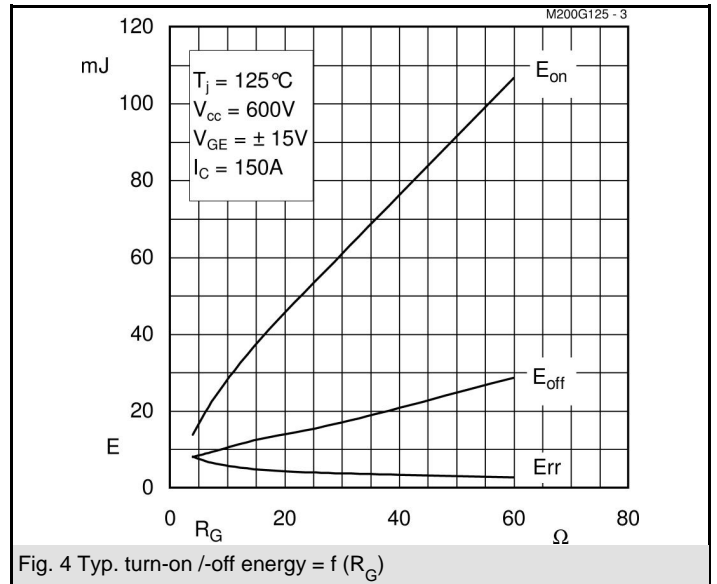
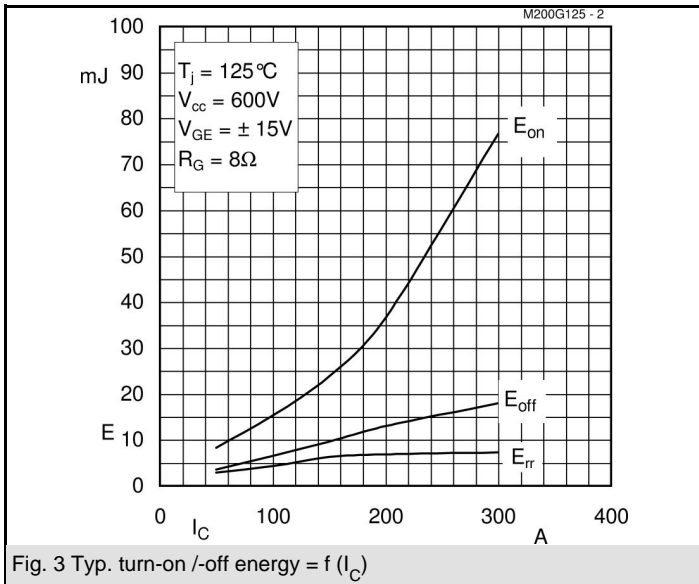
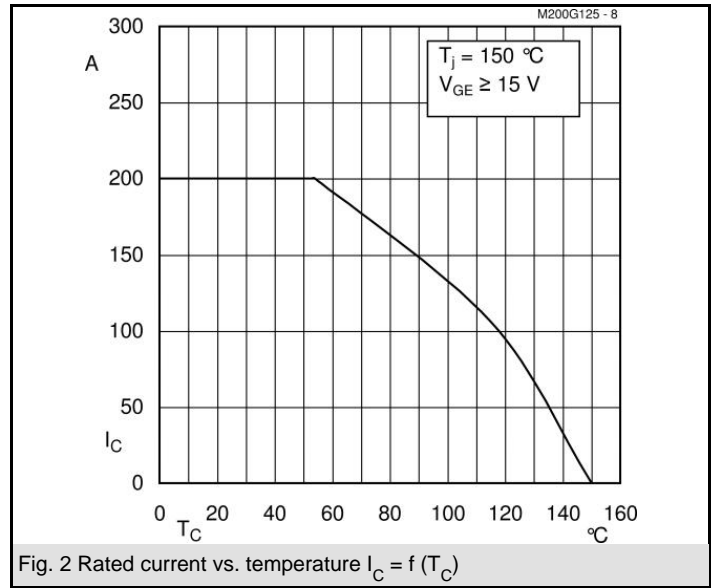
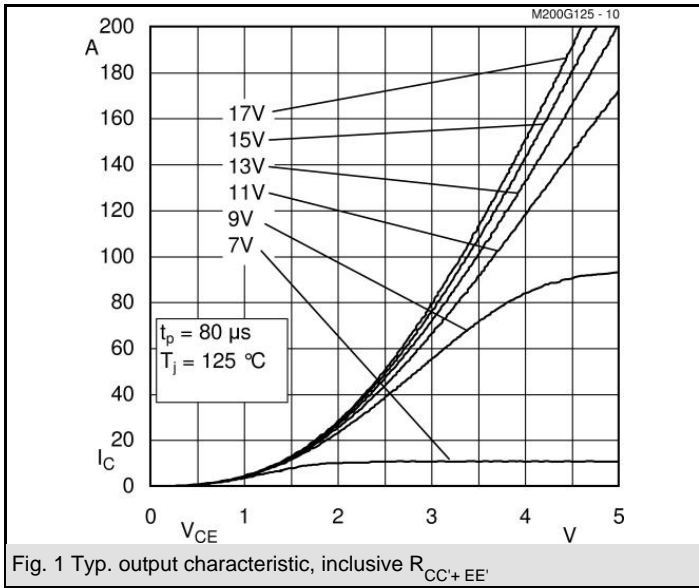
Z_{th}		Conditions	Values	Units
$Z_{th(j-c)I}$				
$R_{\theta j-c}$	$i = 1$		60	mk/W
$R_{\theta j-c}$	$i = 2$		23	mk/W
$R_{\theta j-c}$	$i = 3$		5,9	mk/W
$R_{\theta j-c}$	$i = 4$		1,1	mk/W
$\tau_{th(j-c)}$	$i = 1$		0,0744	s
$\tau_{th(j-c)}$	$i = 2$		0,0087	s
$\tau_{th(j-c)}$	$i = 3$		0,002	s
$\tau_{th(j-c)}$	$i = 4$		0,0015	s
$Z_{th(j-c)D}$				
$R_{\theta j-c}$	$i = 1$		160	mk/W
$R_{\theta j-c}$	$i = 2$		67	mk/W
$R_{\theta j-c}$	$i = 3$		20	mk/W
$R_{\theta j-c}$	$i = 4$		3	mk/W
$\tau_{th(j-c)}$	$i = 1$		0,0536	s
$\tau_{th(j-c)}$	$i = 2$		0,0034	s
$\tau_{th(j-c)}$	$i = 3$		0,077	s
$\tau_{th(j-c)}$	$i = 4$		0,0003	s



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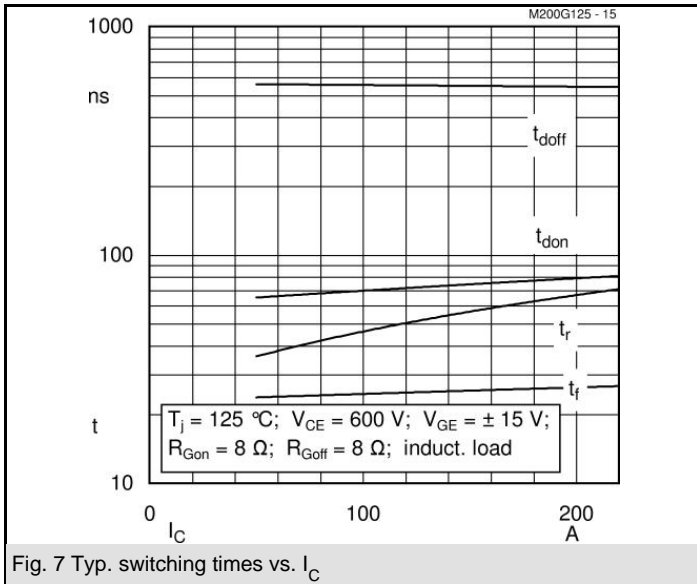


Fig. 7 Typ. switching times vs. I_C

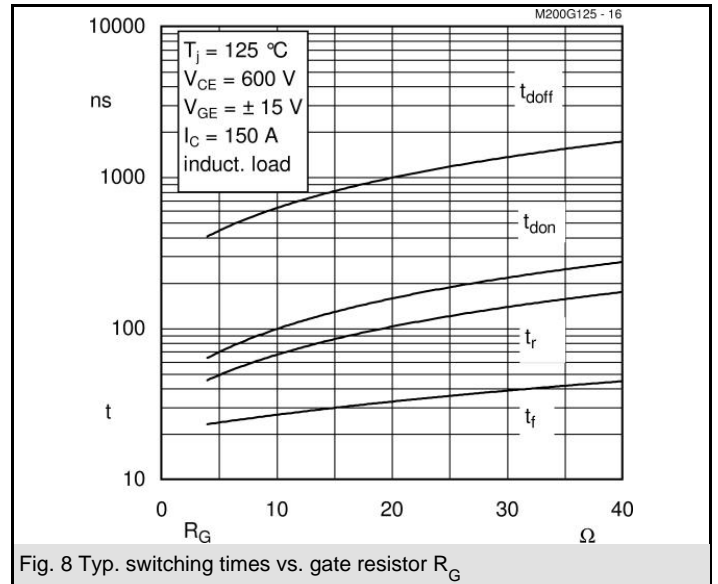


Fig. 8 Typ. switching times vs. gate resistor R_G

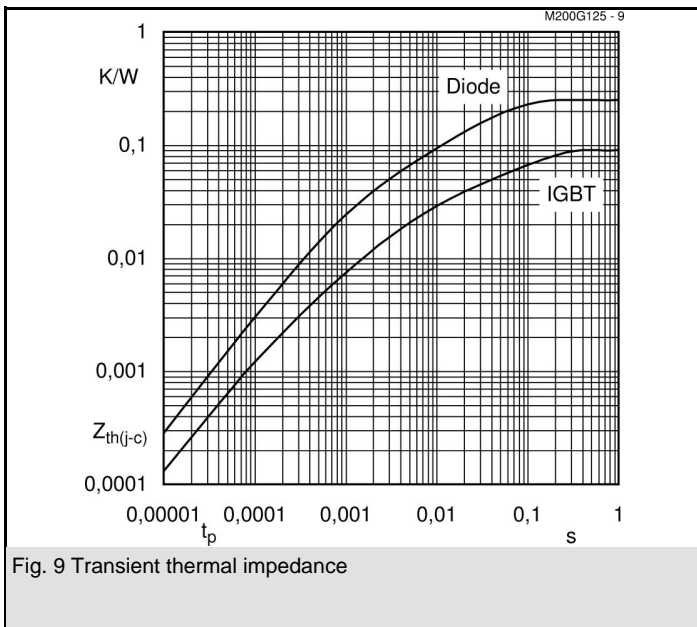


Fig. 9 Transient thermal impedance

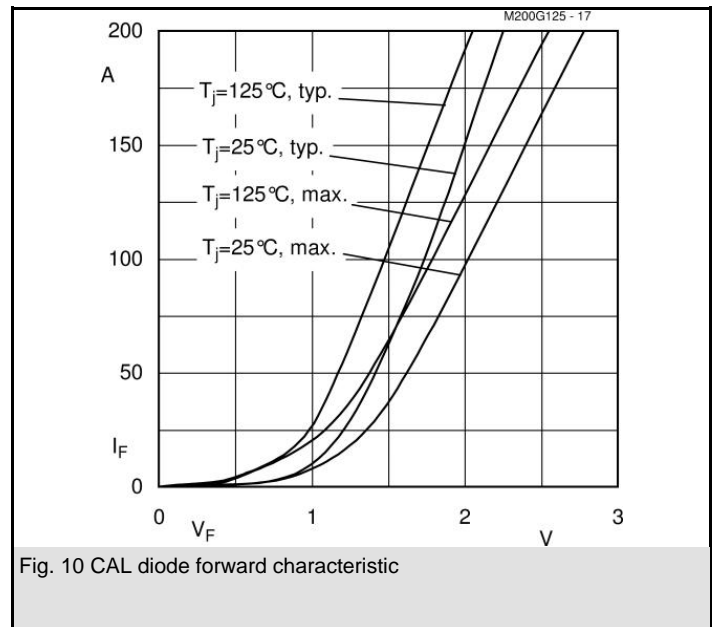


Fig. 10 CAL diode forward characteristic

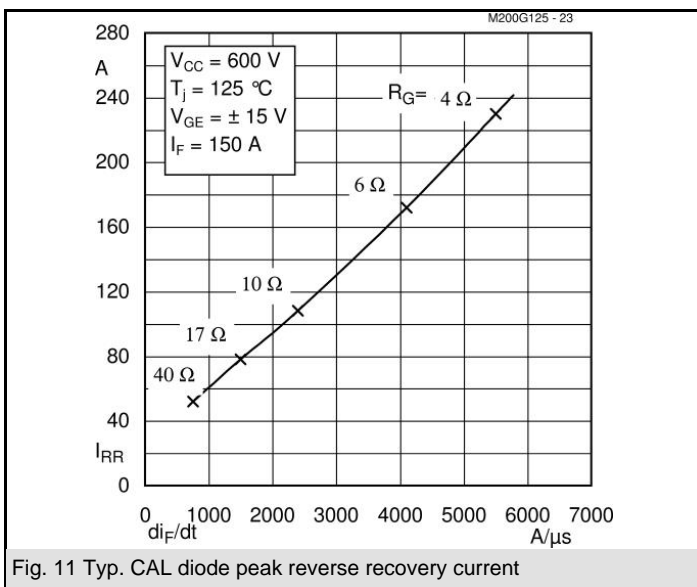


Fig. 11 Typ. CAL diode peak reverse recovery current

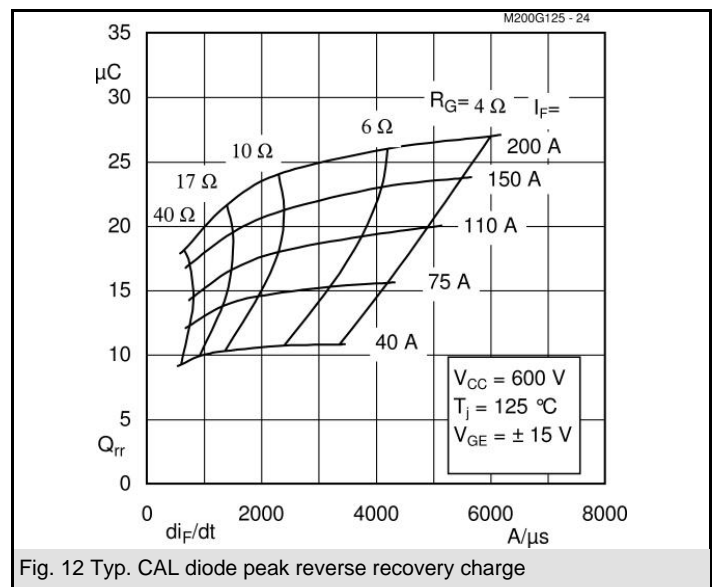


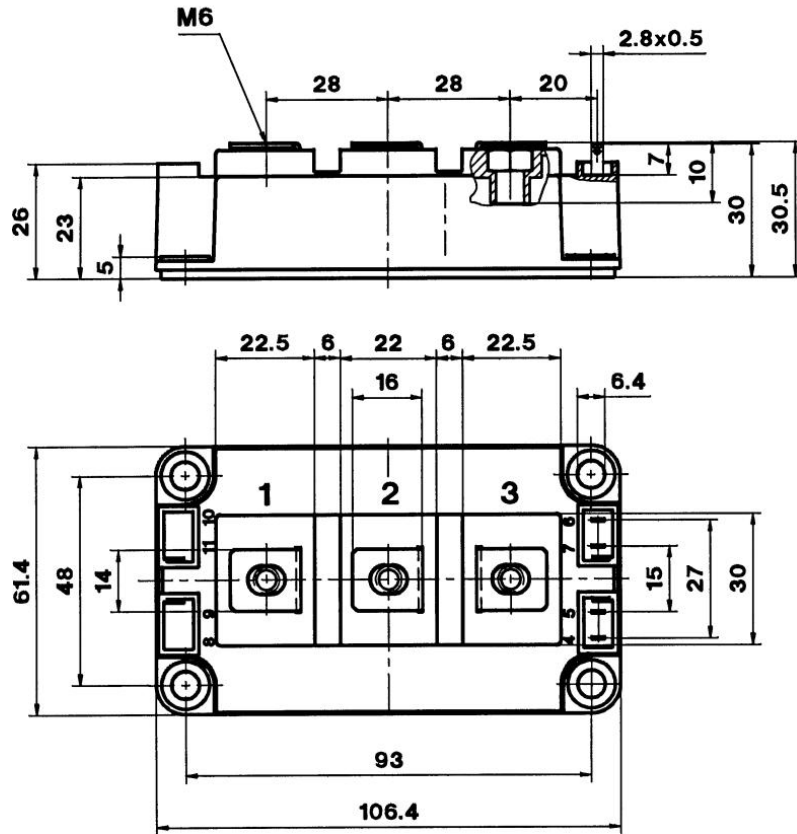
Fig. 12 Typ. CAL diode peak reverse recovery charge

SKM 200GB125D

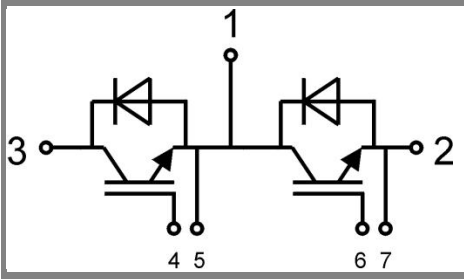
UL Recognized

CASED56

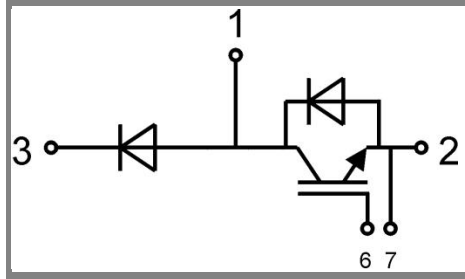
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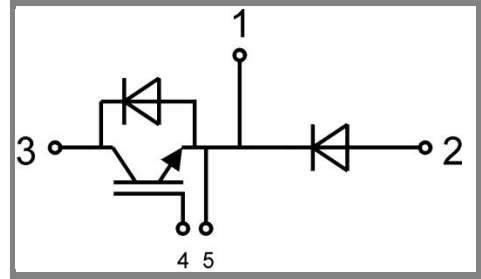
Case D 56



GB Case D 56



GAL Case D 57 (→ D 56)



GAR Case D 58 (→ D 56)